

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10551817	LIN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Cheng, Ichieh	4183

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	452.1-452.2,436,442	1/3/2009	SR
370	310.1,331,338	7/29/2008	SR

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST	1/3/2009	SR

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/SHARAD RAMPURIA/ Primary Examiner.Art Unit 2617
--	---